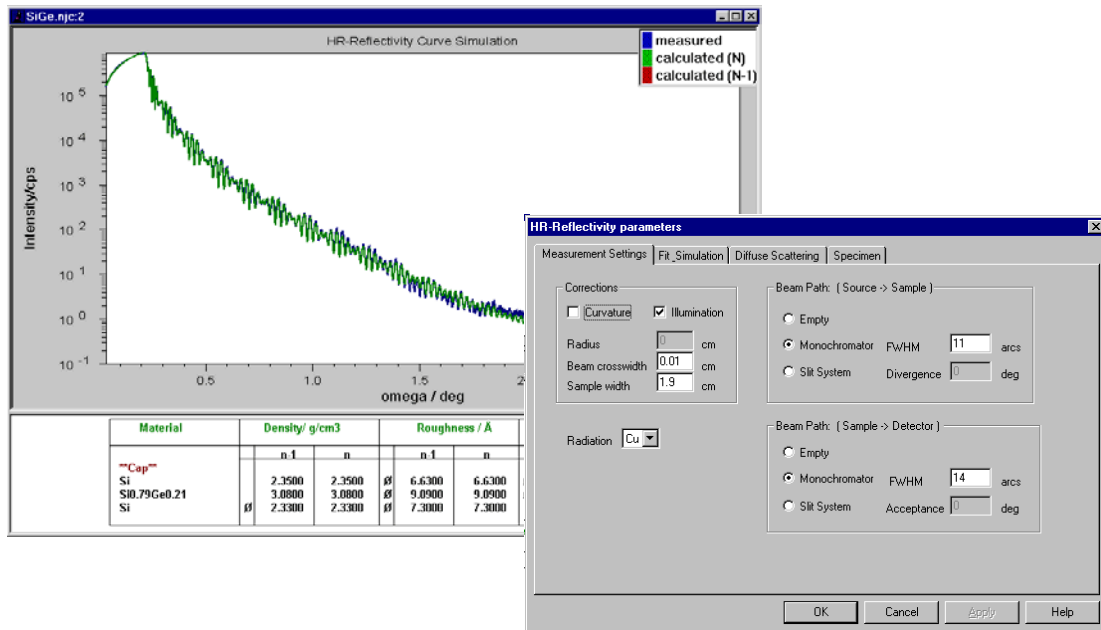


SEIFERT RAYFLEX Analyze

REFLECTIVITY CURVES



Features

- Fit and simulation of X-ray reflectivity curve (in the range of total external reflection) based on recursion formula of Parratt
- Determination of density, thickness and surface/interface roughness of thin films
- Determination of density and surface/ interface roughness of bulk materials
- Consideration of graded interfaces
- Consideration of experimental beam path
- Powerful fitting possibility, choice between 4 different routines
- Consideration of constraints
- Simple interactive determination of film thickness

GE imagination at work

